



ARQ-LVP001

RAD-HARD Octal 500 Mbps Bus LVDS Repeater

FEATURES

- 500.0 Mbps low jitter fully differential data path
- 250 MHz clock channel
- 3.3V power supply
- LVCMOS/LVTTL compatible inputs
- Low power consumption
- 6mA output driver short circuit (OUT+, OUT-)
- Cold sparing on all pins
- 3.5ns Propagation delay in temperature range
- Extended LVDS Input Common Mode [-4; +5] V
- Receiver input threshold ≤ ± 100 mV
- 25mV (typ.) Input hysteresis
- Fail-safe protection circuit
- Radiation tolerant: 300 Krad(Si)
- Latch-up free up to 60 MeVcm²/mg
- ESD tolerance: 8KV
- Packaging: 48-pin Ceramic Quad Flat Pack (COFP)
- ANSI TIA/EIA 644a LVDS Standard Compliant
- Space level

DESCRIPTION

ARQUIMEA'S ARQ-LVP001 device is an Octal Bus Low Voltage Differential Signals (LVDS) Repeater intended for low power and high-speed operation. Data path is fully differential from input to output for low noise generation and low pulse width distortion. The ARQ-LVP001 allows high speed data transmission for point-to-point or multi-drop interconnects. It is specifically designed for the bridging of multiple backplanes in a system while consuming minimal power with reduced EMI.

The Octal LVDS Repeater supports an overall TRI-STATE function that may be used to disable the output stages, disabling the load current, and thus dropping the device to an ultra-low idle power state.

All pins, including CMOS Input, have Cold Spare buffers. The pins will be high impedance when VDD is tied to VSS.

The input buffers of LVDS receiver include an active internal fail-safe circuit that sets the output of the receiver to a known high state when one or the two inputs floating or inputs shorted.

The extended common mode range allows high voltage drops between ground planes without affecting performance.

APPLICATIONS

The ARQ-LVP001 provides the basic bus repeater function. The device operates as a 9 channel LVDS buffer (including Clock) repeating the signal, restoring the LVDS amplitude, allowing to drive another media segment, allowing isolation of segments or long-distance applications.

The intended application of these devices and signaling technique is for both space-wire point-to-point baseband (single termination) and multipoint (double termination) data transmissions over controlled impedance media.

The transmission media may be printed-circuit board traces, backplanes, or cables.

RADIATION HARDENING

PARAMETER	MIN	TYP	MAX	UNIT	COMMENTS
TID	300	-	-	Krad	
SEL	60	-	-	MeVcm ² /mg	Only validated on former design
SEE performance for a GEO orbit	1E-13	-	-	Err/Bit	ARQ-LVR001

More information about radiation hardening features and radiation test conditions is available under request.

AVAILABLE OPTIONS

PRODUCT ORDERING Nº	QUALITY LEVEL	PACKAGE (*¹)	OPERATING TEMPERATURE	VARIANT DETAIL	TERMINAL MATERIAL AND FINISH (*2)	DELIVERY PACK
ARQ-LVP001-03	Engineering Model (* ³)	48 pin CQFP	-55°C to 125°C	NA	D2	15-pieces tray
ARQ-LVP001S03	Space Flight Model (*4)	48 pin CQFP	-55°C to 125°C	NA	D2	15-pieces

(*1) Other packaging options, including raw die format, are also available under request.

- (*2) The terminal material and/or finish shall be in accordance with the requirements of ESCC23500
- (*3) Only electrically tested at 25°C
- (*4) Space level screening and qualification per ESCC9000

ARQ_12104_DSH_004_Issue_05, Date: 01-07-2018





INDEX

FEATURES 1
DESCRIPTION1
APPLICATIONS
RADIATION HARDENING 1
AVAILABLE OPTIONS 1
OVERVIEW3
BLOCK DIAGRAM 3
TRUTH TABLE3
ABSOLUTE MAXIMUM RATINGS 4
RECOMMENDED OPERATING CONDITIONS 4
ELECTRICAL CHARACTERISTICS 5
AC SWITCHING CHARACTERISTICS 6
APPLICATIONS INFORMATION9
PINOUT DESCRIPTION 10
PACKAGE 11
MARKING 12
QUALITY STANDARDS13
IMPORTANT NOTICE14
REVISION HISTORY 15

CONTACT AND ORDERS:.....16

GLOSSARY

VT

BER	Bit Error Ratio
CMRR	Common Mode Rejection Ratio
CQFP	Ceramic Quad Flat Pack
ESD	Electrostatic Discharge
GEO	Geostationary Earth Orbit
IC	Integrated Circuit
1/0	Input/Output
LET	Linear Energy Transfer
LVDS	Low Voltage Differential Signaling
LVTTL	Low Voltage Transistor-Transistor Logic
PSRR	Power Supply Rejection Ratio
RL	Load Resistor
SEE	Single Event Effect
SEL	Single Event Latch-up
TID	Total Ionizing Dose
tf	Fall Time
tr	Rise Time
TTL	Transistor-Transistor Logic
VCM	Common-mode voltage
VID	Differential Input Voltage
vos	Offset voltage

Differential output voltage





OVERVIEW

The ARQ-LVP001 provides the basic bus repeater function. The device operates as a 9 channel LVDS buffer.

Repeating the signal restores the LVDS amplitude, allowing it to drive another media segment. This allows for isolation of segments or long-distance applications.

The intended application of these devices and signaling technique is for both point-to-point baseband (single termination) and multipoint (double termination) data transmissions over controlled impedance media.

BLOCK DIAGRAM

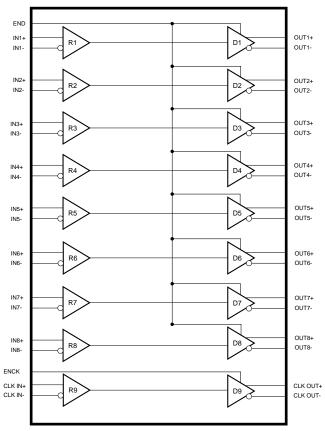


Figure 1: Block diagram

TRUTH TABLE

MODE	ENABLE	INPUTS	OUTPUTS		
IVIODE	END or ENCK	$V_{ID} = V_{IN+} - V_{IN-}$	OUT+	OUT-	
Disabled	L	Χ	Z	Z	
		$V_{ID} > V_{TH}$	Н	L	
Enabled	Н	$V_{TL} < V_{ID} < V_{TH}$?	?	
		$V_{ID} < V_{TL}$	L	Н	
Fail-Safe	Н	OPEN/SC/Terminated for tFS>500ns	Н	L	

Table 1: Truth table

Notes:

(*) L= low Logic Level, H= High Logic Level, X= Irrelevant, Z= High Impedance, '?'=Indeterminate

ARQ_12104_DSH_004_Issue_05, Date: 01-07-2018





ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	VALUE
V_{DD}	DC supply voltage	-0.5 to 4.6V
Vı	TTL/CMOS Input Voltage	-0.5V to 6V
V_{IN}	LVDS Input Voltage	-5V to 6V
T_{STG}	Storage temperature	-65 to +150°C
Τ _J	Maximum junction temperature	+175°C
Tc	Maximum Case temperature	+125ºC
ESD	ESD Last Passing Voltage – HBM	8kV
P_{D}	Power dissipation	1W

Table 2: Absolute Maximum Rating

Note: Stresses outside the listed absolute maximum ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other condition beyond limits indicated in the operational sections of this specification is not recommended. Exposure to absolute maximum rating conditions for extended periods may affect device reliability and performance.

RECOMMENDED OPERATING CONDITIONS

The Recommended Operating as well as derated Conditions according to ECSS-Q-30-11A are presented below

SYMBOL	PARAMETER	OPERATION VALUES	DERATED VALUES
V_{DD}	Power supply voltage	3.0 to 3.6V	3.0 to 3.6V
V	TTL/CMOS input voltage	0 to 5V	0 to 5V
V _{IN}	LVDS input voltage, receiver inputs	-4.6V to 5.6V	-4.6V to 5.6V
V_{CM}	LVDS Input Common Mode Voltage	-4V to 5V	-4V to 5V
T _C	Case temperature range	-55 to +125 °C	+100ºC (Tj=110ºC)

Table 3: Recommended Operating Conditions





ELECTRICAL CHARACTERISTICS

Unless otherwise stated, these specifications apply for VDD = $3.3V\pm0.3V$, $-55^{\circ}C < TC < +125^{\circ}C$

PARAMETER	CONDITION	MIN	MAX	UNIT
		2.0	5V	V
		-0.3	0.8	V
	$V_{DD} = 3.6V, V_{IN} = 3.6V$	-10	+10	μA
		-10	+10	μΑ
·		-3,6	+3,6	μΑ
	337 114	-,-	-,-	
	$R_L = 100\Omega$	247	453	mV
Change in VoD between complementary	$R_L = 100\Omega$		10	mV
Offset Voltage	$R_{L} = 100\Omega V_{OS} = \frac{V_{OH} + V_{OL}}{2}$	1.125	1.375	V
Change in Vos between complementary output states	$R_L = 100\Omega$		50	mV
Imbalance of Differential Offset Voltage during Voltage transition	$R_L = 100\Omega$, $C_L = 1$ pf to 10 pF		150	mV
Output Tri-State Current	Tri-State output (channel disabled), $V_{OUT} = V_{DD}$ or V_{SS}	-5	+5	μΑ
Cold Sparing Leakage Current	$V_{DD} = V_{SS}$, $V_{OUT} = 3.6V$,	-5	+5	μΑ
Output Short Circuit Current	V _{OUT+} =V _{OUT-} =0V	6	24	mA
(Only one output should be shorted at a time)	$V_{OUT+}=V_{OUT-}$	4	12	mA
Differential Input High Threshold		+100	+600	mV
Differential Input Low Threshold	$V_{CM} = -4V \text{ to } +5V$	-600	-100	mV
Differential Input hysteresis (V _{TH} - V _{TL})	$V_{CM} = -4V \text{ to } +5V$	15		mV
Differential Input Fail-Safe High Threshold	$V_{CMI} = -4V \text{ to } +5V$, Hold time>500ns	+10		mV
Differential Input Fail-Safe Low Threshold	$V_{CMI} = -4V \text{ to } +5V$, Hold time>500ns		-10	mV
Differential Input Fail-safe threshold	V _{FSH} - V _{FSL}	20		mV
Common Mode Voltage Range	V _{ID} =±200mV (400mVpp)	-4	+5	V
LVDS Input Current	V_{DD} = +3.6V, V_{CMI} = +1.2V, V_{ID} =±400mV	-10	+10	μΑ
EVDS Input Current	$V_{DD} = +3.6V$, $V_{CMI} = -4V$ to +5V, $V_{IN+}=V_{IN-}=V_{CMI}$	-60	+60	μΑ
Input Current Balance (I _{IN+} -I _{IN-)}	$V_{DD} = +3.6V$, $V_{CM} = -4V$ to +5V, $V_{IN+}=V_{IN-}=V_{CM}$	-6	6	uA
Cold Sparing Lookage Current	$V_{DD} = V_{SS}$, $V_{CMI} = +1.2V$, $V_{ID}=\pm 400 \text{mV}$	-20	+20	μΑ
Colu Sparing Leakage Current	$V_{DD} = V_{SS}$, $V_{CMI} = -4V$ to +5V, $V_{IN+}=V_{IN-}=V_{CMI}$	-60	+60	μΑ
Input Capacitance			3	pF
JRRENT				
Total Supply Current	$R_L=100\Omega$, END/ENCK= V_{DD} , $V_{DD}=3.6V$, $Fq=DC$		130	mA
Tri-State Supply Current	$R_L=100\Omega$, END, ENCK = V_{SS} , $V_{DD}=3.6V$		10	mA
	$R_L=100\Omega$, END/ENCK= V_{DD} , $V_{DD}=3.6V$, $Fq=250MHz$		-50	dB
	DC SPECIFICATIONS (EN, ENK) High-level input voltage Low-level input current Low-level input current Cold Spare Leakage current PUT DC SPECIFICATIONS (OUT+, OUT-) Differential Output Voltage Change in Voo between complementary output states Offset Voltage Change in Vos between complementary output states Imbalance of Differential Offset Voltage during Voltage transition Output Tri-State Current Cold Sparing Leakage Current Output Short Circuit Current (Only one output should be shorted at a time) IVER DC SPECIFICATIONS (IN+, IN-) Differential Input High Threshold Differential Input Low Threshold Differential Input Fail-Safe High Threshold Differential Input Fail-Safe Low Threshold Differential Input Fail-Safe Low Threshold Common Mode Voltage Range LVDS Input Current Input Current Balance (Inn+-Inn+) Cold Sparing Leakage Current Input Capacitance IRRENT Total Supply Current	DC SPECIFICATIONS (EN, ENK) High-level input voltage Low-level input voltage High-level input voltage High-level input current VoD = 3.6V, ViN = 3.6V VoD = 3.6V, ViN = 3.6V VoD = 3.6V, ViN = 0V VoD = 3.6V, ViN = 3.6V VoD = 3.6V	DC SPECIFICATIONS (EN, ENK)	Poc SPECIFICATIONS (EN, ENK) High-level input voltage 2.0 5V

Table 4: DC Electrical Characteristics

ARQ_12104_DSH_004_Issue_05, Date: 01-07-2018





AC SWITCHING CHARACTERISTICS

Unless otherwise stated, these specifications apply for VDD = $3.3V\pm0.3V$, TA = -55° C to $+125^{\circ}$ C.

SYMBOL	PARAMETER	CONDITION	MIN	MAX	UNIT
t _{PHZ}	Disable Time (Active to Tri-State) High to Z	$R_L = 100\Omega$, $C_L = 10pf$		4.5	ns
t _{PLZ}	Disable Time (Active to Tri-State) Low to Z	$R_L = 100\Omega$, $C_L = 10pf$		4.5	ns
t _{РZН}	Enable Time (Tri-State to Active) Z to High	$R_L = 100\Omega$, $C_L = 10pf$		250	ns
t _{PZL}	Enable Time (Tri-State to Active) Z to Low	$R_L = 100\Omega$, $C_L = 10pf$		250	ns
t _{LHT}	Input/Output Low-to-High Transition Time, 20% to 80%	$R_L = 100\Omega$, $C_L = 1$ pf to 10 pF	260	600	ps
t _{HLT}	Input/Output High-to-Low Transition Time, 80% to 20%	$R_L = 100\Omega$, $C_L = 1$ pf to 10 pF	260	600	ps
t _{PLHD}	Propagation Low to High Delay	$R_L = 100\Omega$, $C_L = 10pf$		3,5	ns
T _{PHLD}	Propagation High to Low Delay	$R_L = 100\Omega$, $C_L = 10pf$		3,5	ns
T _{SKEW}	Differential Skew	T _{PHLD} - T _{PLHD}		150	ps
T _{CCS}	Output Channel-to-Channel Skew	$R_L = 100\Omega$, $C_L = 10pf$		500	ps
T _{DDS}	Output Device-to-Device Skew	$R_L = 100 \Omega$, $C_L = 10 pf$		750	ps
tpJ	Periodic Jitter	V _{ID} =±200mV (400mVpp), 50% duty cycle at 250MHz, trise≤ 1ns (20% - 80%)		15	ps
tccı	Cycle to Cycle Jitter	V _{ID} =±200mV (400mVpp), 50% duty cycle at 250MHz, trise≤ 1ns (20% - 80%)		40	ps
t _{PPJ}	Peak to Peak Jitter	$V_{ID} = 2^{(7)}-1$ PRBS pattern at 500Mbps, trise ≤ 1 ns (20% - 80%)		250	ps
t _{DJ}	Deterministic Jitter	$V_{ID} = 2^{(7)}-1$ PRBS pattern at 500Mbps, trise ≤ 1 ns (20% - 80%)		200	ps

Table 5: AC Electrical Characteristics

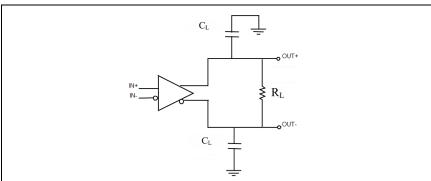


Figure 2: LVDS Output load

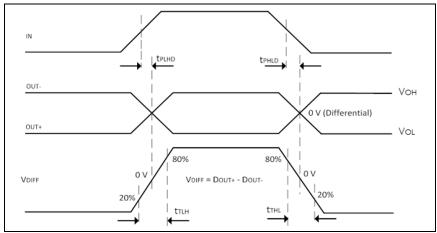


Figure 3: LVDS propagation delay and Output Transition time

ARQ_12104_DSH_004_Issue_05, Date: 01-07-2018

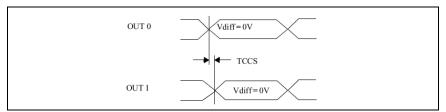


Figure 4: Output channel to channel skew

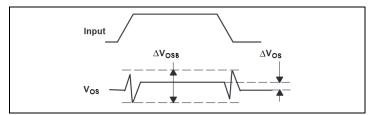


Figure 5: LVDS Offset Voltage

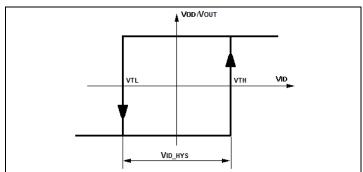


Figure 6: Input Differential Hysteresis

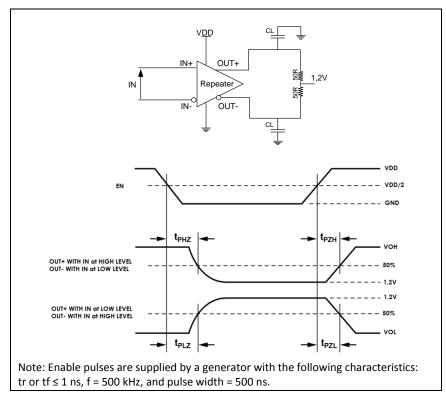


Figure 7: Output active to TRISTATE and TRISTATE to active





APPLICATIONS INFORMATION

Transmission media:

The transmission media may be printed-circuit board traces, backplanes, or cables. (Note: The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media, the noise coupling to the environment, and other application specific characteristics.)

The signal path should be matched in length to avoid any skew in differential lines or between channels.

Input Fail-Safe (comparator and timer):

The ARQ-LVP001 also supports Fail-Safe operation when OPEN or SHORTED inputs are present. Receiver output goes HIGH after 500ns for all fail-safe conditions.

PCB layout and Power System Bypass:

Circuit board layout and stack-up for the ARQ-LVP001 should be designed to provide noise-free power to the device.

Good layout practice also will separate high frequency or high level inputs and outputs to minimize unwanted stray noise pickup, feedback and interference. Power system performance may be greatly improved by using thin dielectrics (4 to 10 mils) for power/ground sandwiches. This increases the intrinsic capacitance of the PCB power system which improves power supply filtering, especially at high frequencies, and makes the value and placement of external bypass capacitors less

critical. A 0.250hm resistor is recommended in the power supply line path. External bypass capacitors should include both RF ceramic and tantalum electrolytic types. RF capacitors may use value of $0.1\mu\text{F}$. Tantalum capacitors may be $2.2\mu\text{F}$. Voltage rating for tantalum capacitors should be at least 5X the power supply voltage being used. It is recommended practice to use two vias at each power pin of the ARQ-LVP001, as well as all RF bypass capacitor terminals. Dual vias reduce the interconnect inductance and extends the effective frequency range of the bypass components.

The outer layers of the PCB may be flooded with additional ground plane. These planes will improve shielding and isolation, as well as increase the intrinsic capacitance of the power supply plane system. Naturally, to be effective, these planes must be tied to the ground supply plane at frequent intervals with vias. Frequent via placement also improves signal integrity in signal transmission lines by providing short paths for image currents which reduces signal distortion. The planes should be pulled back from all transmission lines and component mounting pads a distance equal to the width of the widest transmission line from the internal power or ground plane(s) whichever is greater. Doing so minimizes effects on transmission line impedances and reduces unwanted parasitic capacitances at component mounting pads.





PINOUT DESCRIPTION

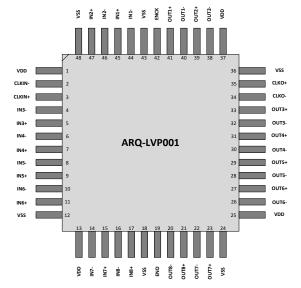


Figure 8: Pinout diagram

№ pin	Name	Туре	Description
5, 7, 9, 11, 15, 17, 45, 47	INn+	LVDS Input	Non-Inverting LVDS input
4, 6, 8 ,10, 14, 16, 44, 46	INn-	LVDS Input	Inverting LVDS input
21, 23, 27, 29, 31, 33, 39, 41	OUTn+	LVDS Output	Non-Inverting LVDS output
20, 22, 26, 28, 30, 32, 38, 40	OUTn-	LVDS Output	Inverting LVDS output
19	END	Digital Input	Logic low on enable puts the LVDS data output into Tri- State and reduces supply current
42	ENCK	Digital Input	Logic low on enable puts the LVDS clock output into Tri- State and reduces supply current
12, 18, 24, 36, 43, 48	VSS	Power	Ground
1, 13, 25, 37	VDD	Power	Power supply
3	CLKIN+	LVDS Input	Non-Inverting Clock LVDS Input
2	CLKIN-	LVDS Input	Inverting Clock LVDS Input
35	CLKO+	LVDS Output	Non-Inverting Clock LVDS Output
34	CLKO-	LVDS Output	Inverting Clock LVDS Output

Table 6: Pinout description





PACKAGE

CQFP48 Drawing

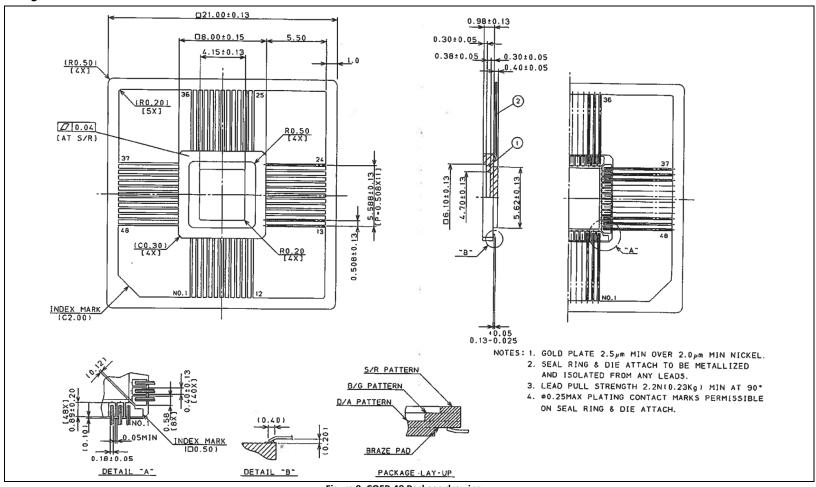


Figure 9: CQFP-48 Package drawing

ARQ_12104_DSH_004_Issue_05, Date: 01-07-2018





Notes:

- 1. An Index mark shall be located adjacent to Pin 1.
- 2. The dimension shall be measured from the seating plane to the base plane.
- 3. The true position pin spacing is 1.27mm between centerlines. Each pin centerline shall be located within ±0.13mm of its true longitudinal position relative to Pin 1 and the highest pin number.
- 4. All exposed metalized areas are gold plated over electroplated nickel per MIL-PRF-38535.
- 5. The lid is electrically connected to VSS.
- 6. Lead finishes are in accordance to MIL-PRF-38535.

MARKING

The laser marked information on the component are:

- ARQUIMEA's symbol Q
- The Entire Part-type
- Traceability information



The traceability information comprises a manufacturing date code, a lot identification and a serial number:

- **Date Code**: Four-digit code number is used for the manufacturing date. The first two digits are the last two figures of the year of manufacture. The last two digits indicate the week of the year (i.e. 01 to 52), during which encapsulation or the final production process occurred.
- Lot and Selected Sublot Identification: If it is necessary to differentiate between more than one lot processed in the same week, a suffix letter (beginning with the letter A) is added to the date code. For a Selected Sublot a second suffix letter (beginning with the letter A) is added to the date code. For a single lot or sublot, letters are omitted (replaced by space).
- **Serial Number**: A serial number consisting of three digits is used. Serial numbers are run sequentially and not duplicated if more than one sub-lot is taken from one production lot.

For Engineering Models, "EM" marking is written after Serial Number





QUALITY STANDARDS

ARQUIMEA INGENIERÍA S.L.U. develops its activities under the premises of quality and sustainability, offering efficient, liable and innovative technologies and solutions to its customers.

ARQUIMEA's Quality Management System meets the requirements of ISO 9100:2010 Aerospace Series and has been audited and certified by the Spanish Association for Standardization and Certification, AENOR.



To meet the highest quality and reliability, ARQUIMEA designs and develops its aerospace product line according to military and space standards.

Our space microelectronic devices are available in the following processes (Screened and Qualified):

- Equivalent to QML 38535 LEVEL Q or V* (on request)
- Equivalent to ESCC 9000*
- *with radiation Qualification

For the procurement in die form, the following processes can be offered on request:

- In accordance with ECSS-Q-ST-60-05C
- Equivalent to QML 38534 LEVEL H or Level K*

Engineering Models are available and tested at 25°C only.





IMPORTANT NOTICE

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REVISION HISTORY

Date Released	Issue	Section	Changes
12-01-2016	Draft A	All	Initial Release copied From ARQ-LVR001 datasheet
	ELECTRICAL CHARACTERISTICS		Parameter update after Electrical
23-09-2016	Draft B	AC SWITCHING CHARACTERISTICS	measurement at Room temperature
13-02-2017	01	FEATURES, APPLICATIONS INFORMATION	Fail-safe feature not available in this version
30-10-2017	02	ELECTRICAL CHARACTERISTICS	Hysteresis feature and Failsafe Threshold Added
18-12-2017	03	TRUTH TABLE	Added table
20-02-2018	04	AVAILABLE OPTIONS PACKAGE MARKING	Added description, Version ARQ-LVP001-02 removed Notes Added Added Information
01-07-2018	05	ELECTRICAL CHARACTERISTICS	Parameter update after Electrical Measurement at room temperature





Space Technology Partner

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ARQ_12104_DSH_004_Issue_05, Date: 01-07-2018